

A Complete Bibliography of Publications in *Technometrics* for the decade 1990–1999

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Title word cross-reference

(≥ 2) [Sin92]. 2^{k-p} [BH97, Bis94]. $2^{k-p} \times s$ [BS97]. 2^n [SWC97]. 2^{n-k} [SCF97]. 2^{n-p} [SWC97]. 3 [Ber98]. * [DL90a]. C_P [Mal95, vdVtBM97]. D [AB97, DJ94, Ney94]. D_s [AB97]. F [Ano00, SBD98]. k [Ode90, Sin92]. $k(\geq 2)$ [Sin83]. L_p [Spo90]. M [Gri97b, Ode90]. $N \neq 2^k$ [LIV96]. P [GK90, ME99, Cha93, Lin93a, Lin95a, ZM94]. \prod [Bre91a, Bre91b, Fri91, Gu91, HT91]. X [WJ92]. Y [WJ92].

-D [Ber98]. **-efficient** [Lin95a, Lin93a]. **-Estimators** [Gri97b]. **-Norm** [Spo90]. **-Optimal** [DJ94]. **-Optimality-Based** [Ney94]. **-Optimum** [AB97]. **-Spline** [ME99]. **-Value** [Cha93].

1 [Fam95, Zie98o]. **100** [Zie94a]. **101** [Zie99a]. **1750** [Zie92a]. **1930** [Zie99b]. **1984** [Zie91f, Zie91e]. **1988** [Zie90d].

2 [Ber96b, Sch93a, Zie98p, Zie99-44]. **20th** [Bro90b]. **25** [Sin92]. **29** [Ste90b].

3 [Fox91, Kus93, Sar93, Zie99-45]. **31** [BT98]. **34** [HR94]. **35** [DPL⁺94, Lin95a].

40 [Sen99b].

5 [Zie90f, Zie99n]. **5.0** [Zie96m].

84g [Sin92]. **88e** [Ste90b].

9000 [Zie93n]. **90f** [BT98]. **'92** [Zie95r]. **94c** [DPL⁺94]. **'96** [Zie98u]. **97** [Zie99k]. **99h** [Sen99b].

Aage [Kel97]. **Aabaranel** [Sti97]. **Aberration** [BS99, HCV98, SCF97].

Abraham [Zie98-35]. **Abrupt** [Rie94a, Yas95]. **Abuse** [Zie90z].

Accelerated

[BE94, DH92, EM95, ML95, MEL98, MM94, Sch91c, Spe91, Mee91b, Sam90].

Acceptance [HL95, MT92, Tan93, Wes90]. **Acceptance-Sampling** [MT92].

Accompany [Gun90]. **Accountants** [Zie95-40]. **Accumulation**

[Hab90, HW90b, HW90a, Hir90, Nai90b, YDB90]. **Accuracy**

[CB93, ES94, OUH93]. **Accurate** [AKO94]. **Achieving** [Dun96]. **Action**

[BL94]. **Active** [VS96, VS98]. **Adams** [Zie95-50]. **Adaptive**

[HP97, Har92a, ST90a, Zha94, Har91d, Por97b]. **Added** [Coo96a].

Added-Variable [Coo96a]. **Additional** [ES94, Nel93]. **Additive** [dV92].

Adelchi [DeV99, Lei99]. **Adequacy** [Zie94c]. **Adhikari** [Loh94]. **Adjusted**

[Ano91f, Haw91b]. **Adjustment** [BK92a, BK92b, BL94, JV93, Luc98, LG99,

Mac92, Tuc92, VV92, WG92, Cha93, Fal99]. **Administrators** [Pro93b].

Adrian [DeV99]. **Adrienne** [Bru94]. **Advanced**

[Ada96, Dea95, Tho90a, Zie94d]. **Advances**

[Wol96, Zie96-34, Tor99, Zie94e, Zie96a, Zie98c, Zie98d, Zie98e]. **Advection**

[MS95]. **Advection-Dispersion** [MS95]. **Adventures** [Wen93]. **Affi**

[Zie92e, Zie97h]. **Aft** [Rol93, Zie99o]. **after** [GS92]. **Aggarwal** [Kha95].

Agresti [Hap91]. **Ahlbom** [Zie95i]. **AI** [Zie95c]. **Aided**

[And90, LaL95, WC92, Zie98f, Zie92e, Zie97h]. **Air** [GK93]. **Aitken**

[Zie96-42]. **Aitkin** [Moo91]. **Akaike** [Zie99-36, Zie99-36]. **Alain** [Cab98].

Alan [Hap91, Lee90, Sea94, Win93, Zie98r]. **Albert**

[Eas90, Goo92a, Zie98-34, Zie98i]. **Alberto** [Fal99, Job99, Lei91]. **Albright**

[Zie99z]. **Alessandro** [Dog99]. **Alexander** [Goo95, Jac95, Sha97a, Weh91].

Algebra [Zie98-30, Zie99w]. **Algorithm** [Kus98, MN95, QY98, RvD99].

Algorithmic [Mad96, Ngu96a, TFV93, VTFD92]. **Algorithms**

[LW97, Was97, Jon92, IHMT95, Sar90, Wol91]. **Aliasing** [CHW97].

All-or-None [VV94]. **Allan** [Mul97, Nan94, Sar94a]. **Aldredge** [Zie94m].

Allen [Gra90, Bax92]. **Allison** [Zie97-38]. **Allocation** [ES94, Yin91]. **Alreck**

[Zie99-52]. **Alsultan** [Zie99y]. **Alsup** [McL95]. **Alternative** [Fai94]. **Alvin** [Boo98, Mat96]. **American** [Lew92, Zie99-33]. **Amitava** [Bem96]. **Amount** [McA90]. **Analyses** [Bar92a, Ko95a, Sch91c, VV99, Dri92, Mee91b, Zie97y].

Analysing [Zie96b]. **Analysis**

[ACV99, Alb93, Alt99, Ano99e, Bar95, Bas97, Bax96b, BNC87, BS97, Bla94, Bow91, Boy90, Boy96, Bro92, Bry92, Cab94, Cal94, Cam90, Car97, CHB90, Che94, CH96a, Chi91, Chu91, Cob91, Cox93, Cox96, CB94, Dea91, Deh90, Dic91, DS93, Dre91, Elt90, Emp99, Eub90, Fai91, Far97, FL97, Fot96, Fox98, FL95, Fre95, Gle91, Goo95, Got92, Gra98, Gre98, GC91, Gru90, Hab90, Hag96, HW90b, HW90a, HW91, HS93, Han98, Hap92, Har92a, Has91, Hec96, Hir90, Hir96, HS97, Jac95, Jol90, KLR91, Kia92b, Kia93b, Kii92, KTTS90, LN95, Law98, Lee99, Lin92, Lwi94, Lyn97b, Lyn99, MW90, Maz93, McA90, MEL98, MME98, Mil90, MMY93, MS95, Nai90b, NW93, Nel93, OUH93, Pap95, Per92, Per98, Pet93, Pet99, Pri98, Pro92a, Rao98]. **Analysis** [Ray93, Rig93, STC99, Sau98, Sch95, Sch96b, Sch93c, Sch93b, Sch91d, Sco91, Sha97c, Sim91, Sri92, Ste91, SP95, Taa91, Tam96, Tan98, Tom95, Vin92, WL97, Wat96, Weh95, Wel90, WN97, YDB90, Yas92, ZP94, Zie90-27, Zie90v, Zie90q, Zie90f, Zie90b, Zie91q, Zie91h, Zie91o, Zie92f, Zie92q, Zie93h, Zie93g, Zie93f, Zie94o, Zie94-29, Zie94p, Zie95y, Zie95j, Zie95-46, Zie95-50, Zie95-36, Zie96m, Zie96t, Zie96i, Zie96-29, Zie96-39, Zie96-38, Zie96l, Zie97-38, Zie97x, Zie97p, Zie97-36, Zie97c, Zie97j, Zie97z, Zie97-30, Zie97-40, Zie98-44, Zie98g, Zie98r, Zie98b, Zie99-38, Zie99-31, Zie99i, Zie99d, Zie99x, vN90, Bay99, Ber92a, Boo97, DeV99, Dea94, Dov93, Geo94, Geo98, Gol99, Goo92a, Gra90, Gro99, Gun99, Had92, Ham96, Han90, Han97, Hap91, Hec95, Hei90, Job99].

Analysis

[Jol93, Koh94, LaL95, Lin90, Liu92b, Mat96, Mat97, Mat98, Nai94, Nan94, Not92b, Por93, Pri93, Ruk97a, Sam99b, Sau94, Sch96a, Sch96c, Sen94b, Ter92, Tim95, Ver90, Web90, Win90, Wol96, Zel94, Zha92, Zie90o, Zie90c, Zie92k, Zie92e, Zie93-27, Zie94u, Zie94f, Zie94x, Zie94-36, Zie95-48, Zie95v, Zie95l, Zie96-50, Zie96a, Zie96c, Zie97h, Zie97r, Zie97l, Zie97f, Zie97-36, Zie97-33, Zie97t, Zie97-37, Zie98-39, Zie98m, Zie99-34, Zie99c, Zie99-35, Zin93, Car95, Cra94, Kia93a, Len93, Sti97, Tsa91, Zie91q, Zie95d, vT91].

Analysis-of-Means-Type [WN97]. **AnalysisPart** [Sha95]. **Analysts**

[LeP90b]. **Analytic** [BR95]. **Analytical** [Hil95, LaL95, RL95, Zie93l].

Analyzing [CHW97, Pat91, Gro96]. **and/or** [CR91]. **Anders**

[Kel97, Zie92a, Zie99b]. **Andersen** [Kle94, Sau98, SG99]. **Anderson**

[Moo91, Gre94, Hap92, Lee90, Zie94-36]. **Andor** [Sea91]. **Andre**

[Zie94d, Zie97y, Zie98t]. **Andreas** [Zie98-46]. **Andrej** [KB94]. **Andrew**

[Ang92, Cox96, Ens95, Han98, Lar95, Pri93, Zie97-33]. **Andrzej** [Mor93b].

Ani [Loh94]. **Anil** [Mat98, Sar90]. **Ann** [Soy95, Zie99r]. **Anne**

[Bor97b, Gun90]. **Annealing** [Deu96]. **Annie** [Bor97b]. **Announcement**

[Mor98b]. **ANOVA** [BT98, BT89, Van92b, Nai96, Zie93b]. **Ansell** [Han97].

Anthony [Cal94, LeP90a]. **Antoniadis** [Zie97-43]. **Anxiety** [Cly94]. **Any**

[Zie99a]. **Anyone** [God90]. **Aoki** [Zie98f, Zie92p]. **APC** [HP92].

Application

[Ano98e, BCL98a, BCL98b, CR98, DP97, ET96, Jen92, Kaf94, Lam92, LT96, Oma91, Rob98, Sch98a, SP95, TH93, VTFD92, Bor98, Der90, Rie94a, Zie98v].

Applications

[Ber96a, Boo90, Bow91, Bru93a, Cal94, CR96, Cox96, CC95, Dea97, Gla98, Hag90, HR92, Hea94, HL97, Kan95, LaL92, LPR92, LW97, LLP⁺99, LN96, McC94, Nan94, OM96a, OM96b, Pig91, Rie94b, Smi93, Spe96b, Ste91, Swe96, Tho90a, Tuc96, Weh91, Won98, Wyc96, Zie92a, Zie94d, Zie94-27, Zie96-37, Zie99w, HR94, Zie95-50, Zie98s, Bar92b, Bar95, Bax92, Bax96a, Boo94b, Boo98, Bro90a, Chi91, Dea95, Dob96, Fai91, Gri99, Gue90, Jac95, Jon91a, Kah94, Kir92, LuV90, Mas99, Mil90, Mor93a, Not92a, Sar94b, Sin97, Tor95, Van92a, Was97, Zie91d, Zie92m, Zie95o, Zie95y, Zie98d, Zie99e, Jon90, Zie98f, Zie98g].

Applied [Bil91, Dre91, Goo91, Gra94, Jam96, Liu92a, Mat98, Mor93b, Nel95, NO96, Rie97, Sau97, Sen94b, Ste96a, Ste96b, Ver90, WVYB97, Zie91j, Zie91b, Zie94t, dVU96, Zie97-44, Ale95, Cuc92, DeV99, Dri92, Elt90, Eub93, Gas94, Gol99, Gra98, Gri97a, Gun99, Han98, Hec95, Jan94, Kia90, Kia92b, Kia93b, LC98, Lyn97b, Mar97, Nai94, Rag91, Ste98, Tho99, Wat90, Win90, Woz91, Zie90b, Zie90c, Zie90a, Zie92b, Zie93c, Zie95e, Zie96d, Zie96c, Zie97-44, Zie98h, Zie99c, Zie99d, vN90]. **Apply** [Pro92a]. **Applying** [Che98].

Approach [Cam98, CHW97, CM93b, CM93a, EH96, FL97, Gri96, Gun93, HO93, Hah93, Hec96, HLD98, LST93, ME99, Mar99, Mil94, Mor92, Ngu96a, Pet93, Sam99a, Ste99, Tho90b, USM99, VS96, VM91, Won92, Zie93-34, Zie94j, Zie95b, Ada91, Bal93, Bor97c, Boy90, Bul96, Deh90, Edg92, Fre92, Gre94, Haw90, Lar95, Liu92a, Lyn95, Mad96, MA92, Qiu95, Sar94a, Stu94, Vin92, Wil98, Zie91j, Zie93-29, Zie94t, Zie94s, Zie94z, Zie95-29]. **Approaches** [Ale98, Sim97]. **Appropriate** [HC91]. **Approximate** [CDKS92, DS93].

Approximation [KM99, Jol90]. **ARCH** [Zie99e]. **Archer** [Zie99-48].

Archetypal [CB94]. **Architecture** [Ara92]. **Argentesi** [War90]. **Arising**

[MS95]. **Arlene** [Zie96-47, Zie99-52]. **Arlinghaus** [Zie98-33]. **Armed**

[Yin91]. **Armstrong** [Zie97n, Zie90i, Zie92h]. **Arnljot** [Van96b]. **Arnold**

[Bax92, Far93, Zie99-37, Wol92]. **Arrays** [HS99, Ngu96b, WW92]. **Art**

[Gut92]. **Arthur** [Gil92, Law98, Spo90, Zie98f, Fai91]. **Articles** [Bor97a].

Artificial [Zie95f]. **Ashish** [Chi91]. **Aspects**

[MS90, O'D97, Zie98-41, Zie94-28, Bas99, Zie95g]. **ASQC** [Zie97o, Zie97-31].

Assembled [Bis97]. **Assessing** [TC90]. **Assessment**

[Dow94, GD94, Got94c, Got94b, Jou94, Liu99, Rut94, Tor94, Wad99, WB94,

Zie95n, Zie99-28, Pla96, Zie91n, Zie95m, Zie98y, Zie99j]. **Assessments**

[Zie90y]. **Assignments** [Zie91b]. **Association** [Jol97]. **Assumed** [DJ94].

Assumption [Kun97]. **Assumptions** [Col92, St.94]. **Assurance**

[Lew92, Spa99, Zie93l, Zie99-33, Bru93b, Gan97, Jai95, Sea94, Sha92].

Astrom [Har91d]. **Astronomy** [Zie98g, Coa94]. **Astrostatistics** [Sin98].

Asymptotic [Ang90b, Ano90f, SS89]. **Asymptotically** [Sch92b].

Asymptotics [SP95]. **Athanasios** [Gro92]. **Atkinson** [Whe93].

Atmospheric [Ram96, Zie96-38]. **Attributes** [Car93, NW93]. **Auditing**

[Zie96q]. **Augmenting** [RH95]. **Autocorrelations** [ZP94]. **Automated** [Kir93, Run90]. **Availability** [Pla96]. **Avenhaus** [Dav99, War90]. **Average** [Bax90, DP91, FHT90, Gan95, Hes95, Hun90b, LWCR92, LS90b, LS90c, MH90, Van96a, WM90]. **Averill** [Dea94]. **Award** [Zie96-46]. **Ayton** [Zie95-42]. **Ayyub** [Bry99]. **Azzalini** [DeV99, Lei99].

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 HP97, Hea94, HLD98, HCV98, LIV96, Ode90, RL95, Sch91c, ST90a, Sim88,
 SS97, VV99, Wes90, WC92]. **Two-Component** [RL95]. **Two-Level**
 [BS99, DL90a, FL97, HCV98, LIV96, Sch91c, WC92]. **Two-Sample**
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